

OpenATE PE32C

3U PXI High Performance Dynamic Digital PE Card

- 32 input / output channels, dynamically configurable on 256 I/O sets
- 64 M of on-board vector memory per channel
- 2.5,3.3, 5 VIH per board
- 100 MHz data rate
- Data Capture mode can capture real time data up to 100 MHz in 64 M depth.
- Supports 4 Data Formats
- Operates as a stand-alone card or with up to 7 additional synchronous slave boards
- API & Pattern Editor



Description

The PE32C represents a new level of performance and capabilities for PXI-based digital instrumentation. Based on the proven architecture of the PE32C, the PE32C offers high performance pin electronics and an enhanced timing generator in a compact, 3U PXI form factor. Each card can function as a stand-alone digital subsystem or if required, multiple cards can be interconnected, supporting up to 256 bi-directional pins (8 boards). The PE32C also supports deep pattern memory by offering 64 M of on-board vector memory with per channel and dynamic 256 sets direction control and with test rates up to 100MHz. New data capture mode can capture data in 100MHz with 64M depth.

Features

The PE32C supports switchable VIH levels from 2.5V ~ 5V per board. The PE32C offers 1 timing sets, 2 driver TG Edges, 2 strobe TG Edges. 1 Format sets and four drive data formats are supported:

RTZ (Return To Zero), RTO (Return To One), NRZ (Non Return To Zero), SBC (Surround By Complement) which can providing flexibility to create a variety of bus cycles and waveforms to test board and box level products.

On-Board Memory

The PE32C offers 64 M of vector memory per channel. Programmable pattern cycle times up to 2^{32} or infinite. There are pattern symbols including 0, 1, L, H, X, Z, J, Q.

Compatibility

All OpenATE Interfaces PXI cards comply with the PXI Specification 2.0 (issued Aug. 2000)

Software

The PE32C is supplied with API and Pattern Editor. Pattern Editor is a software tool that edits test patterns.

Application

- Automatic Test Equipment(ATE)
- Consumer Digital Functional Test
- Digital Pattern Generation
- Power Management Device Testing
- Hybrid and Digital IC Testing

OpenATE Inc.

The Open Solution for IC Tester

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Specifications

• Pin Electronics		• Logic Sequencer	
I/O Channels	32, per board with 256 I/O sets	Pattern Symbols	0, 1, L, H, X, Z, J, Q
Test rate	100MHz	LMSYNC to PXI Trigger Bus	For Sync With other Instruments
Input Level (Vih)	2.5V ,3.3V, 5V per board	Ignore Fail By LM Address	YES
• Timing		Vector Memory	64M(length) × 32(channels)
Period Resolution	5nS	Programmable pattern cycle times	2 ³² or infinite
Pin TG Edge Resolution	5nS	• Trigger	
Minimum Pulse Width	10nS	EXT TTL Trigger	1
Timing Sets	1	• Physical Properties	
Driver TG Edges	2, per pin resource	Bus Interface	PXI
Strobe TG Edges	2, per pin resource	Dimensions	3U
• Formatter		Power Requirements	3.3V@3A, 5V@3A
Format Sets	1	System Clock	200MHz
RTZ, Return To Zero RTO, Return To One NRZ, Non Return To Zero SBC, Surround By Complement		Bus & Signals	8 PXI Trigger bus lines for parallel test
		• Environmental	
		Operating Temperature	0 ~ 50°C
		Storage Temperature	-20 ~ 70°C
		• Software	API & Pattern Editor
		• Maximum boards in one system	8
		*One PMU is responsible to 8 I/O channels	
• PXI Compliance	All OpenATE Interfaces PXI cards comply with the PXI Specification 2.0 (issued Aug, 2000)		

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